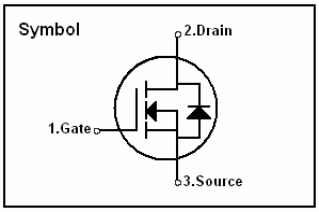
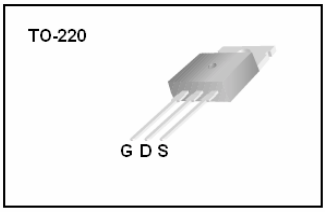
FQP8N60/FQPF8N60

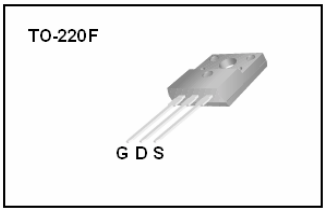
600V N-Channel MOSFET

Features

- 7.5A,600V,RDS(on)=1.0Ω@VGS=10V
- Low gate charge
- Low C_{rss} (typical 23pF)
- Fast switching
- 100% AvalancheTested
- Improved dv/dt capability
- ROHS product







General Description

This Power MOSFET is produced using AOKE's advanced planar stripe, DMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. These devices are well suited for high efficiency switch mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

Absolute Maximum Ratings

Symbol	Parameter	FQP8N60	FQPF8N60	Units
VDSS	Drain to Source Voltage	600		V
ID	Continuous Drain Current(@TC = 25°C)	7.5	7.5*	A
	Continuous Drain Current(@TC = 100°C)	4.4	4.4*	A
IDM	Drain Current Pulsed (Note 1)	28	28*	A
VGS	Gate to Source Voltage	±30		V
EAS	Single Pulsed Avalanche Energy (Note 2)	420		mJ
EAR	Repetitive Avalanche Energy (Note 1)	14.7		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5		V/ns
PD	Total Power Dissipation(@TC = 25 °C)	147	48	W
	Derating Factor above 25 °C	1.18	0.38	W/ °C
TSTG, TJ	Operating Junction Temperature & Storage Temperature	-55 ~ 150		°C
TL	Maximum Lead Temperature for soldering purpose, 1/8 from Case for 5 seconds.	300		°C

Thermal Characteristics

Symbol	Parameter	FQP8N60	FQPF8N60	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.85	2.6	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ	0.5	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Electrical Characteristics (TC = 25 °C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0V, I_D = 250uA	600	-	-	V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature coefficient	I_D = 250uA, referenced to 25 °C	-	0.65	-	V/°C
I_{DSS}	Drain-Source Leakage Current	V_{DS} = 600V, V_{GS} = 0V	-	-	10	uA
		V_{DS} = 480V, T_C = 125 °C	-	-	100	uA
I_{GSS}	Gate-Source Leakage, Forward	V_{GS} = 30V, V_{DS} = 0V	-	-	100	nA
	Gate-source Leakage, Reverse	V_{GS} = -30V, V_{DS} = 0V	-	-	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250uA	2.0	-	4.0	V
$R_{DS(ON)}$	Static Drain-Source On-state Resistance	V_{GS} =10 V, I_D = 3.75A	-	1.0	1.2	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{GS} =0 V, V_{DS} =25V, f = 1MHz	-	1380	1800	pF
C_{oss}	Output Capacitance		-	115	150	
C_{rss}	Reverse Transfer Capacitance		-	23	30	
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	V_{DD} =300V, I_D =7.5A, R_G =25Ω (Note 4, 5)	-	30	70	ns
t_r	Rise Time		-	80	170	
$t_{d(off)}$	Turn-off Delay Time		-	125	260	
t_f	Fall Time		-	85	180	
Q_g	Total Gate Charge	V_{DS} =480V, V_{GS} =10V, I_D =7.5A (Note 4, 5)	-	40	48	nC
Q_{gs}	Gate-Source Charge		-	6	-	
Q_{gd}	Gate-Drain Charge(Miller Charge)		-	20	-	

Drain-Source Diode Ratings and Characteristics

Symbl	Parameter	Test Conditions	Min.	Typ.	Max.	Unit.
I_S	Continuous Source Current	Integral Reverse p-n Junction	-	-	7.5	A
I_{SM}	Pulsed Source Current	Diode in the MOSFET	-	-	28	
V_{SD}	Diode Forward Voltage	I_S=7.5A, V_{GS} =0V	-	-	1.4	V
t_{rr}	Reverse Recovery Time	I_S=7.5A, V_{GS}=0V,dI_F/dt=100A/us	-	415	-	ns
Q_{rr}	Reverse Recovery Charge	I_S=7.5A, V_{GS}=0V,dI_F/dt=100A/us	-	4.6	-	uC

※ NOTES
1. Pulse width limited by maximum junction temperature
2. L = 15.7mH, I_{AS} =7.5A, V_{DD} = 50V, R_G = 25Ω , Starting T_J = 25°C
3. I_{SD} ≤ 7.5A, di/dt ≤ 300A/us, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C
4. Pulse Test : Pulse Width ≤ 300us, Duty Cycle ≤ 2%
5. Essentially independent of operating temperature

Fig 1. On-State Characteristics

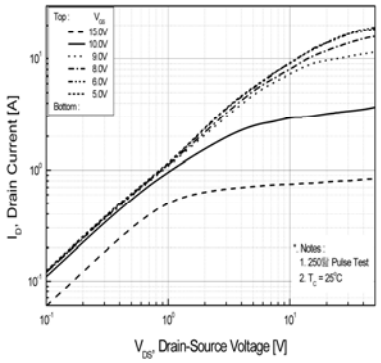


Fig 2. Transfer characteristies

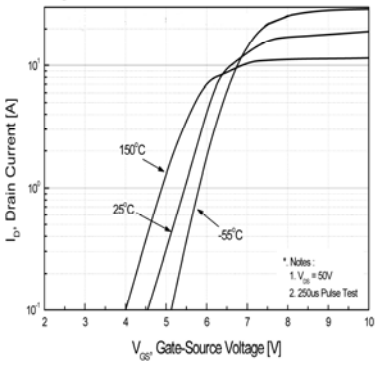


Fig 3. On Resistance Variation vs. Drain Current and Gate Voltage

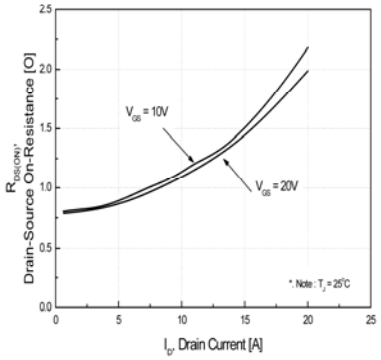


Fig 4. On State Current vs.

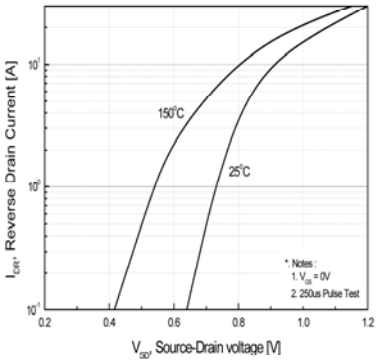


Fig 5. Capacitance Characteristics (Non-Repetitive)

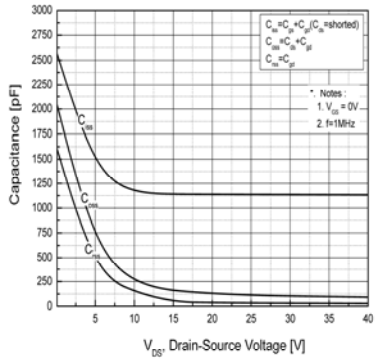


Fig 6. Gate Charge Characteristics

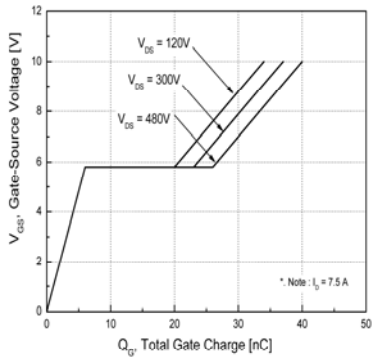


Fig 7. Breakdown Voltage Variation vs. Junction Temperature

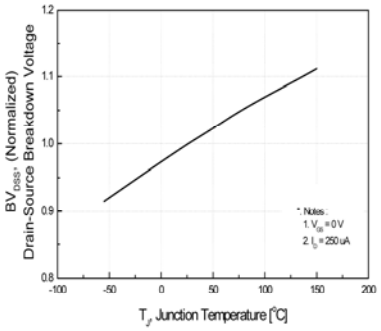


Fig 8. On-Resistance Variation vs. Junction Temperature

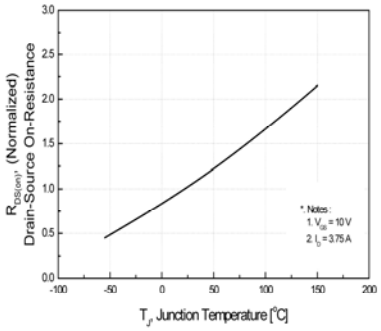


Fig 9-1. Maximum Safe Operating Area for FQP8N60

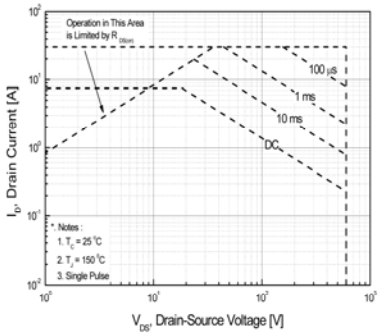


Fig 9-2. Maximum Safe Operating Area for FQPF8N60

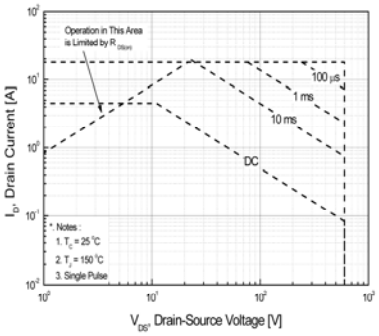


Fig 10. Maximum Drain Current vs. Case Temperature

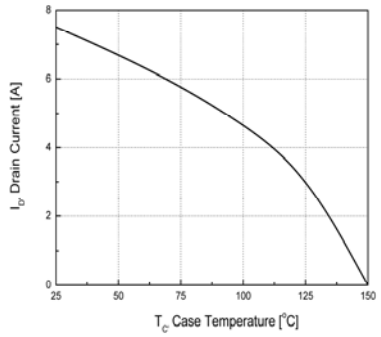


Fig 11-1 . Transient Thermal Response Curve for FQP8N60

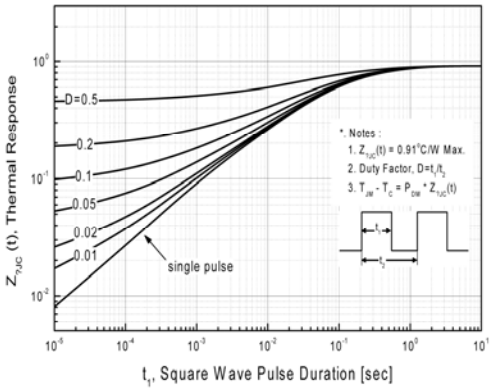


Fig 11-2 . Transient Thermal Response Curve for FQPF8N60

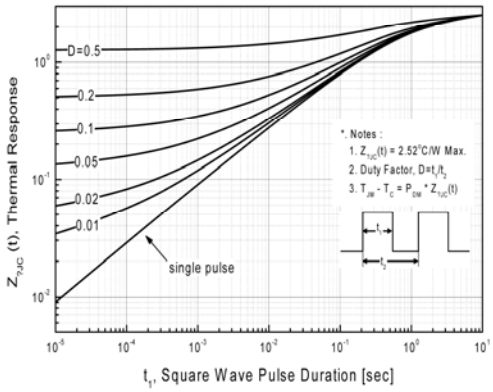


Fig. 12. Gate Charge Test Circuit & Waveforms

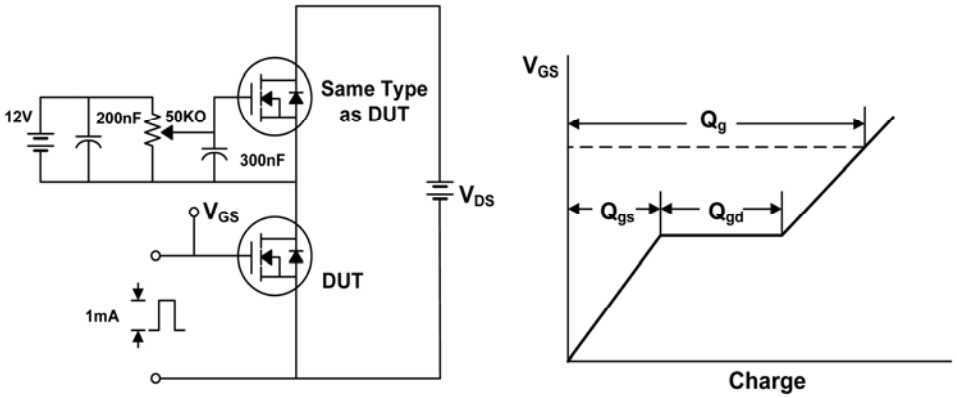


Fig 13. Switching Time Test Circuit & Waveforms

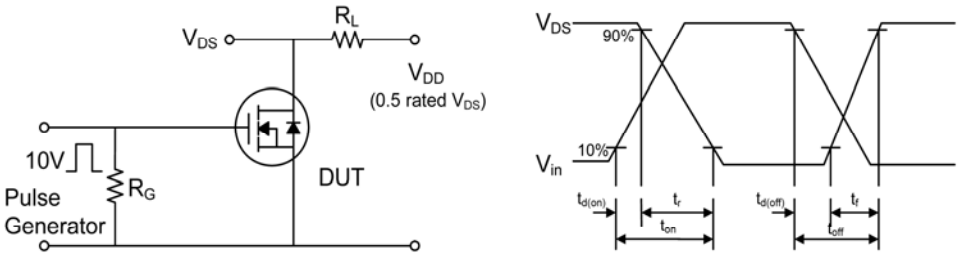


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

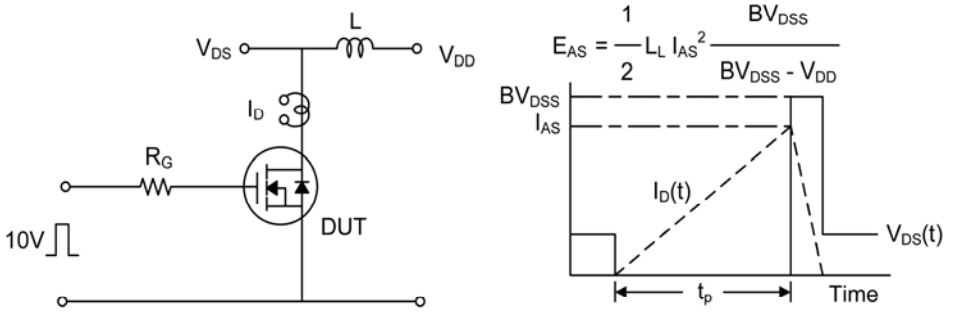


Fig. 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms